

ITS4200S-SJ-D

Smart High-Side NMOS-Power Switch

Data Sheet

Rev 1.0, 2012-09-01

Standard Power



Smart High-Side NMOS-Power Switch

ITS4200S-SJ-D



1 Overview

Features

- · CMOS compatible input
- Switching all types of resistive, inductive and capacitive loads
- · Fast demagnetization of inductive loads
- Very low standby current
- Optimized Electromagnetic Compatibility (EMC)
- · Open drain diagnostic output for overtemperature and short circuit
- · Open load detection in OFF-state with external resistor
- Overload protection
- Current limitation
- Short circuit protection
- · Thermal shutdown with restart
- Overvoltage protection (including load dump)
- Reverse battery protection with external resistor
- Loss of GND and loss of Vbb protection
- Electrostatic Discharge Protection (ESD)
- Green Product (RoHS compliant)

ITS4200S-SJ-D is not qualified and manufactured according to the requirements of Infineon Technologies with regards to automotive and/or transportation applications.



The ITS4200S-SJ-D is a protected 200m Ω single channel Smart High-Side NMOS-Power Switch in a PG-DSO-8 package with charge pump, CMOS compatible input and diagnostic feedback.

Product Summary

Overvoltage protection $V_{\rm SAZmin}$ = 62V Operating voltage range: 6V < $V_{\rm S}$ < 52V On-state resistance $R_{\rm DSON}$ = typ 150m Ω Nominal load current $I_{\rm LNOM}$ = 1.2A

Operating Temperature range: $T_i = -40$ °C to 125°C

Application

- All types of resistive, inductive and capacitive loads
- Power switch for 12V, 24V and 45V DC applications with CMOS compatible control interface
- · Open drain diagnosis feedback for overtemperature and short circuit
- Driver for electromagnetic relays
- Power managment for high-side-switching with low current consumption in OFF-mode

Туре	Package	Marking
ITS4200S-SJ-D	PG-DSO-8	I200SD

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PG-DSO-8

PG-DSO-8



Block Diagram and Terms

2 Block Diagram and Terms

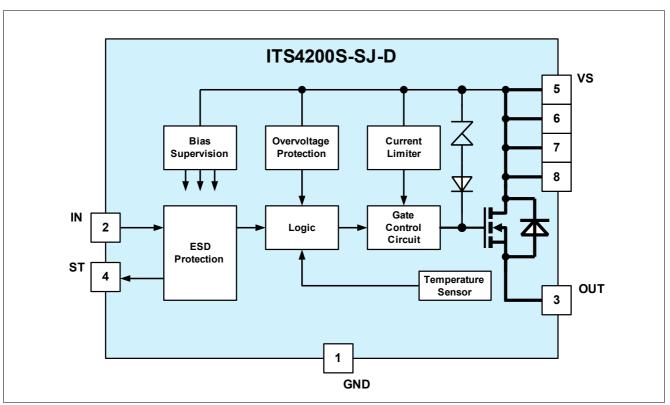


Figure 1 Block diagram

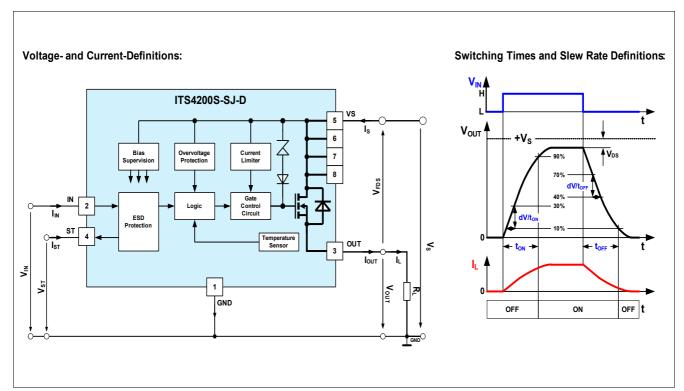


Figure 2 Terms - parameter definition



Pin Configuration

3 Pin Configuration

3.1 Pin Assignment

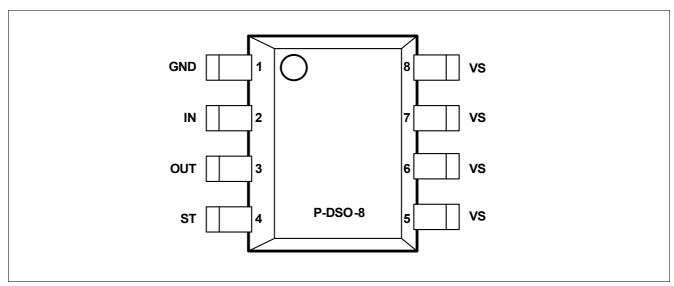


Figure 3 Pin configuration top view, PG-DSO-8

3.2 Pin Definitions and Functions

Pin	Symbol	Function
1	GND	Logic ground
2	IN	Input, controles the power switch; the powerswitch is ON when high
3	OUT	Output to the load
4	ST	Status flag; diagnosis feedback; NMOS open drain
5, 6, 7, 8	VS	Supply voltage (design the wiring for the maximum short circuit current and also for low thermal resistance)



General Product Characteristics

4 General Product Characteristics

4.1 Absolute Maximum Ratings

Table 1 Absolute maximum ratings $^{1)}$ at T_j = 25°C unless otherwise specified. Currents flowing into the device unless otherwise specified in chapter "Block Diagram and Terms"

Parameter	Symbol	ymbol V	Value	S	Unit	Note / Test Condit ion	Number
		Min.	Тур.	Max.			
Supply voltage VS	1		"	"	1		1
Voltage	V_{S}			52	V		4.1.1
Voltage for short circuit protection	V_{SSC}			36	V		4.1.2
Output stage OUT			•				
Output Current; (Short circuit current see electrical characteristics)	I_{OUT}			self limited	А		4.1.3
Input IN						'	
Current	I_{IN}	-5		5	mA		4.1.4
Status ST			-	-			
Current	I_{ST}	-5		5	mA		4.1.5
Temperatures						'	•
Junction Temperature	$T_{\rm j}$	-40		125	°C		4.1.6
Storage Temperature	$T_{\rm stg}$	-55		125	°C		4.1.7
Power dissipation			•				
Ta = 25 °C ²⁾	P_{tot}			1.4	W		4.1.8
Inductive load switch-off energy dissipa	tion					'	•
Tj = 125 °C; IL= 1A ³⁾	E_{AS}			125	mJ	single pulse	4.1.9
ESD Susceptibility	•	•	•	•	•	-	
ESD susceptibility (input pin)	V_{ESD}	-1		1	kV	HBM ⁴⁾	4.1.10
ESD susceptibility (all other pins)	V_{ESD}	-5		5	kV	HBM ⁵⁾	4.1.11

¹⁾ Not subject to production test, specified by design

Note: Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Integrated protection functions are designed to prevent IC destruction under fault conditions described in the data sheet. Fault conditions are considered as "outside" the normal operating range. Protection functions are neither designed for continuous nor repetitive operation.

Data Sheet 5 Rev 1.0, 2012-09-01

²⁾ Device on 50mm*50mm*1.5mm epoxy PCB FR4 with 6 cm2 (one layer, 70mm thick) copper area for Vbb connection. PCB is vertical without blown air

³⁾ Not subject to production test, specified by design

⁴⁾ ESD susceptibility HBM according to EIA/JESD 22-A 114.

⁵⁾ ESD susceptibility HBM according to EIA/JESD 22-A 114.



General Product Characteristics

4.2 Functional Range

Table 2 Funtional Range

Parameter	Symbol		Values		Unit	Note /	Number
		Min.	Тур.	Max.		Test Condition	
Nominal Operating Voltage	V_{S}	6		52	V	$V_{\rm S}$ increasing	4.2.1

Note: Within the functional range the IC operates as described in the circuit description. The electrical characteristics are specified within the conditions given in the related electrical characteristics table.

4.3 Thermal Resistance

Note: This thermal data was generated in accordance with JEDEC JESD51 standards. For more information, go to www.jedec.org.

Table 3 Thermal Resistance¹⁾

Parameter	Symbol		Values	;	Unit	Note / Test Condition	Number
		Min.	Тур.	Max.			
Thermal Resistance - Junction to pin5	$R_{ m thj-pin5}$		23.3		K/W		4.3.1
Thermal Resistance - Junction to Ambient - 1s0p, minimal footprint	R _{thJA_1s0p}		128.7		K/W	2)	4.3.2
Thermal Resistance - Junction to Ambient - 1s0p, 300mm ²	$R_{\mathrm{thJA_1s0p_300mm}}$		70.1		K/W	3)	4.3.3
Thermal Resistance - Junction to Ambient - 1s0p, 600mm ²	R _{thJA_1s0p_600mm}		65.6		K/W	4)	4.3.4
Thermal Resistance - Junction to Ambient - 2s2p	$R_{\mathrm{thJA_2s2p}}$		55.4		K/W	5)	4.3.5
Thermal Resistance - Junction to Ambient with thermal vias - 2s2p	$R_{\mathrm{thJA_2s2p}}$		53.5		K/W	6)	4.3.6

- 1) Not subject to production test, specified by design
- 2) Specified R_{thJA} value is according to Jedec JESD51-3 at natural convection on FR4 1s0p board, footprint; the Product (Chip+Package) was simulated on a 76.2 x 114.3 x 1.5 mm board with 1x 70 μ m Cu.
- 3) Specified R_{thJA} value is according to Jedec JESD51-3 at natural convection on FR4 1s0p board, Cu, 300mm²; the Product (Chip+Package) was simulated on a 76.2 x 114.3 x 1.5 mm board with 1x 70 μ m Cu.
- 4) Specified R_{thJA} value is according to Jedec JESD51-3 at natural convection on FR4 1s0p board, 600mm²; the Product (Chip+Package) was simulated on a 76.2 x 114.3 x 1.5 mm board with 1x 70 μ m Cu.
- 5) Specified R_{thJA} value is according to Jedec JESD51-2,-5,-7 at natural convection on FR4 2s2p board; the Product (Chip+Package) was simulated on a 76.2 x 114.3 x 1.5 mm board with 2 inner copper layers (2 x 70 μ m Cu, 2 x 35 μ m Cu).
- 6) Specified R_{thJA} value is according to Jedec JESD51-2,-5,-7 at natural convection on FR4 2s2p board with two thermal vias; the Product (Chip+Package) was simulated on a 76.2 x 114.3 x 1.5 mm board with 2 inner copper layers (2 x 70μm Cu, 2 x 35μm Cu. The diameter of the two vias are equal 0.3mm and have a plating of 25um with a copper heatsink area of 3mm x 2mm). JEDEC51-7: The two plated-through hole vias should have a solder land of no less than 1.25 mm diameter with a drill hole of no less than 0.85 mm diameter.

Data Sheet 6 Rev 1.0, 2012-09-01



Electrical Characteristics

5 Electrical Characteristics

Table 4 $V_{\rm S}$ = 12V to 42V; $T_{\rm j}$ = -40°C to 125°C; all voltages with respect to ground, currents flowing into the device unless otherwise specified in chapter "Block Diagram and Terms". Typical values at $V_{\rm s}$ = 13.5V, $T_{\rm i}$ = 25°C

Parameter	Symbol		Value	s	Unit	Note / Test Condition	Number
		Min.	Тур.	Max.			
Powerstage		11	II.		ļ	1	1
NMOS ON Resistance	R_{DSON}		150	200	mΩ	$I_{\rm OUT}$ = 1A; $T_{\rm j}$ = 25°C; 9V < $V_{\rm S}$ < 52V; $V_{\rm IN}$ = 5V	5.0.1
NMOS ON Resistance	R_{DSON}		250	350	mΩ	$\begin{split} I_{\text{OUT}} &= \text{1A; } T_{\text{j}} = \text{125°C;} \\ 9\text{V} &< V_{\text{S}} < \text{52V;} \\ V_{\text{IN}} &= \text{5V} \end{split}$	5.0.2
Nominal Load Current; device on PCB ¹⁾	I_{LNOM}	1.2			А	$T_{\rm pin5}$ = 85°C	5.0.3
Timings of Power Stages ²⁾					<u>'</u>		
Turn ON Time(to 90% of $V_{\rm out}$); $V_{\rm S}$ to GND transition of $V_{\rm IN}$	t_{ON}		80	180	μs	$V_{\rm S}$ =13.5V; $R_{\rm L}$ = 47 Ω	5.0.4
Turn OFF Time (to 10% of $V_{\rm out}$); $V_{\rm S}$ to GND transition of $V_{\rm IN}$	t_{OFF}		80	200	μs	$V_{\rm S}$ =13.5V; $R_{\rm L}$ = 47 Ω	5.0.5
ON-Slew Rate (10 to 30% of $V_{\rm out}$); L to H transition of $V_{\rm IN}$	SR _{ON}		0.7	2.0	V/µs	$V_{\rm S}$ =13.5V; $R_{\rm L}$ = 47 Ω	5.0.6
OFF-Slew Rate; $dV_{\rm OUT}/dt_{\rm ON}$ (70 to 40% of $V_{\rm out}$); H to L transition of $V_{\rm IN}$	SR _{OFF}		0.9	2.0	V / µs	$V_{\rm S}$ =13.5V; $R_{\rm L}$ = 47 Ω	5.0.7
Under voltage lockout (charge pur	np start-sto	p-resta	art)				
Supply undervoltage; charge pump stop voltage	V_{SUV}			4	V	$V_{\rm S}$ decreasing -40°C < $T_{\rm i}$ < 85°C	5.0.8
Supply undervoltage; Charge pump stop voltage	V_{SUV}			5.5	V	$V_{\rm S}$ decreasing $T_{\rm i}$ = 125°C	5.0.9
Supply startup voltage; Charge pump restart voltage	V_{SSU}		4	5.5	V	$V_{\rm S}$ increasing	5.0.10
Current consumption			1				
Operating current	I_{GND}		8.0	2	mA	V_{IN} = 5V	5.0.11
Standby current	I_{SSTB}			15	μΑ	V_{IN} = 0V; V_{OUT} = 0V -40°C < T_{i} < 85°C	5.0.12
Standby current	I_{SSTB}			18	μA	V_{IN} = 0V; T_{i} = 125°C	5.0.13
Output leakage current	I_{OUTLK}			5	μA	V_{IN} = 0V; V_{OUT} = 0V	5.0.14
Protection functions 3)	1	1	I		1		1
Initial peak short circuit current limit	I_{LSCP}			9	А	$T_{\rm j}$ = -40°C; $V_{\rm S}$ = 20V; $V_{\rm IN}$ = 5.0V; $t_{\rm m}$ = 150 μ s	5.0.15
Initial peak short circuit current limit	I_{LSCP}		6.5		Α	$T_{\rm j}$ = 25°C; $V_{\rm S}$ = 20V; $V_{\rm IN}$ = 5.0V; $t_{\rm m}$ = 150 μ s	5.0.16



Electrical Characteristics

Table 4 $V_{\rm S}$ = 12V to 42V; $T_{\rm j}$ = -40°C to 125°C; all voltages with respect to ground, currents flowing into the device unless otherwise specified in chapter "Block Diagram and Terms". Typical values at $V_{\rm s}$ = 13.5V, $T_{\rm j}$ = 25°C

Parameter	Symbol Values		Unit	Note /	Number		
		Min.	Тур.	Max.		Test Condition	
Initial peak short circuit current limit	I_{LSCP}	4			А	$T_{\rm j}$ =125°C; $V_{\rm S}$ = 20V; $V_{\rm IN}$ = 5.0V; $t_{\rm m}$ = 150 μ s	5.0.17
Initial peak short circuit current limit 4)	I_{LSCP}		5		Α	$V_{\rm S}$ > 40V; $V_{\rm IN}$ = 5.0V; $t_{\rm m}$ = 150 $\mu{\rm s}$	5.0.18
Repetitive short circuit current limit $T_{\rm i} = T_{\rm Trip}$; see timing diagrams	I_{LSCR}		6		Α	$V_{\rm IN}$ = 5.0V; $V_{\rm S}$ < 40V	5.0.19
Repetitive short circuit current limit $T_{\rm j} = T_{\rm jTrip}$; see timing diagrams	I_{LSCR}		4.5		Α	$V_{\rm IN}$ = 5.0V; $V_{\rm S}$ > 40V	5.0.20
Output clamp at $V_{\text{OUT}} = V_{\text{S}} - V_{\text{DSCL}}$ (inductive load switch off)	V_{DSCL}	59	63		V	$I_{\rm S}$ = 4mA	5.0.22
Overvoltage protection $V_{\text{OUT}} = V_{\text{S}} - V_{\text{ONCL}}$	V_{SAZ}	62			V	$I_{\rm S}$ = 4mA	5.0.23
Thermal overload trip temperature	T_{jTrip}	150			°C		5.0.24
Thermal hysteresis	T_{HYS}		10		K		5.0.25
Reverse Battery ⁵⁾						-	+
Continuous reverse battery voltage	V_{SREV}			52	V		5.0.26
Forward voltage of the drain-source reverse diode	V_{FDS}		600		mV	I_{FDS} = 200mA; V_{IN} = 0V; T_{j} = 125°C	5.0.27
Input interface; pin IN		1	"			,	-
Input turn-ON threshold voltage	V_{INON}	2.2			V		5.0.28
Input turn-OFF threshold voltage	V_{INOFF}			0.8	V		5.0.29
Input threshold hysteresis	V_{INHYS}		0.4		V		5.0.30
Off state input current	I_{INOFF}	1		25	μΑ	$V_{IN} = 0.7V$	5.0.31
On state input current	I_{INON}	3		25	μΑ	V _{IN} = 5.0V	5.0.32
Input resistance	R_{IN}	2.0	3.5	5.0	kΩ		5.0.33
Status output (NMOS open drain); pi	n ST		•				
Status output zener voltage	V_{STZ}	5.4	6.1	6.8	V	$I_{\rm ST}$ = 1.6mA	5.0.34
Status output low voltage	V_{STLO}			0.4	V	I_{ST} = 1.6mA; T_{j} < 25°C	5.0.35
Status output low voltage	V_{STLO}			0.6	V	$I_{\rm ST}$ = 1.6mA $T_{\rm j}$ < 125°C	5.0.36
Status leakage current	I_{STLK}			2	μΑ	$V_{\rm ST}$ = 5V; $T_{\rm i}$ < 105°C	5.0.37
Status invalid time after positive input slope ⁶⁾⁷⁾	$t_{\sf dP}$		120	160	μs	V _S = 13.5V	5.0.38
Status invalid time after negative input slope ⁸⁾⁹⁾	$t_{\sf dN}$		250	400	μs	V _S = 13.5V	5.0.39
Diagnostic characteristics	-1	1		1	1	1	1
Short circuit detection voltage	V_{OUTSC}		2.8		V		5.0.40
Open load detection voltage ¹⁰⁾	V_{OUTOL}		3	4	V		5.0.41
Internal pull down resistor ¹¹⁾	R_{OUTPD}		200		kΩ	V_{OUT} = 4V	5.0.42
I 	*						

Data Sheet 8 Rev 1.0, 2012-09-01



Electrical Characteristics

- 1) Device on 50mm x 50mm x 1,5mm epoxy FR4 PCB with 6cm² (one layer copper 70um thick) copper area for supply voltage connection. PCB in vertical position without blown air.
- 2) Timing values only with high slewrate input signal; otherwise slower.
- 3) Integrated protection functions are designed to prevent IC destruction under fault conditions described in the data sheet. Fault conditions are considered as "outside" normal operating range. Protection functions are not designed for continuous repetitive operation.
- 4) No subject to production test; specified by design.
- 5) Requires a 150W resistor in GND connection. The reverse load current trough the intrinsic drain-source diode of the power-MOS has to be limited by the connected load. Power dissipation is higher compared to normal operation due to the votage drop across the drain-source diode. The temperature protection is not functional during reverse current operation! Input current has to be limited (see max ratings).
- 6) No delay time after overtemparature switch off and short circuit in on-state.
- 7) No subject to production test; specified by design.
- 8) No delay time after overtemparature switch off and short circuit in on-state.
- 9) No subject to production test; specified by design.
- 10) External pull up resistor required for open load detection in off state.
- 11) No subject to production test; specified by design.

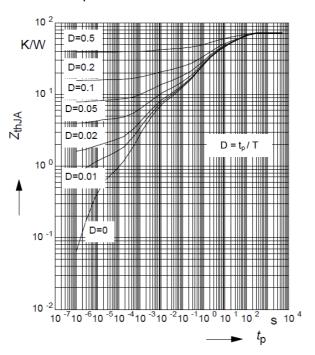
Data Sheet 9 Rev 1.0, 2012-09-01



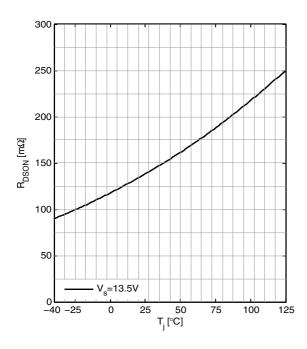
6 Typical Performance Graphs

Typical Characterisitics

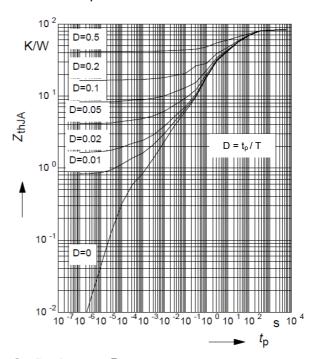
Transient Thermal Impedance $Z_{\rm thJA}$ versus Pulse Time $t_{\rm p}$ @ 6cm² heatsink area



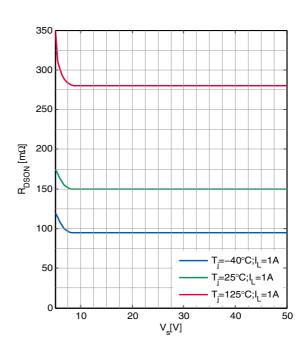
On-Resistance $R_{\rm DSON}$ versus Junction Temperature $T_{\rm i}$



Transient Thermal Impedance Z_{thJA} versus Pulse Time t_p @ min footprint



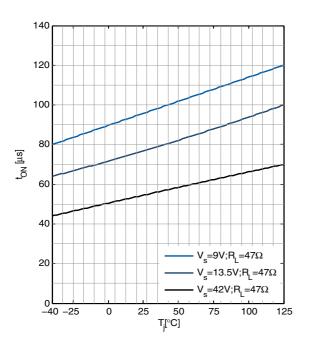
On-Resistance R_{DSON} versus Supply Voltage V_{S}



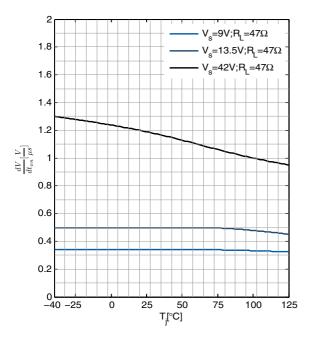


Typical Characterisitics

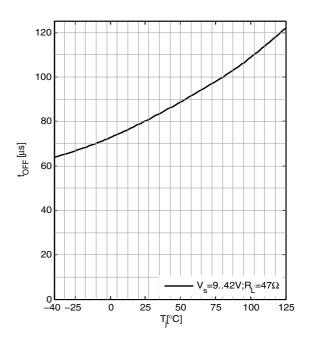
Switch ON Time $t_{\rm ON}$ versus Junction Temperature $T_{\rm i}$



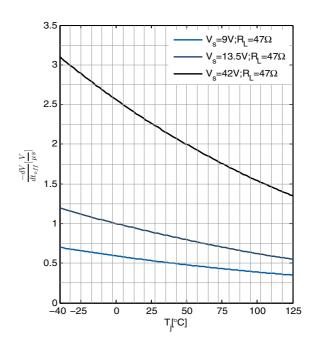
ON Slewrate SR_{ON} versus Junction Temperature T_i



Switch OFF Time t_{OFF} versus Junction Temperature T_{j}



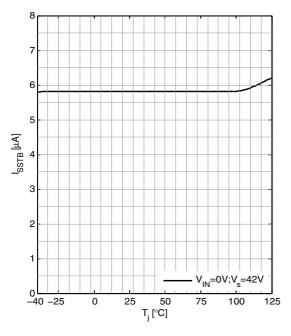
OFF Slewrate SR_{OFF} versus Junction Temperature T_i



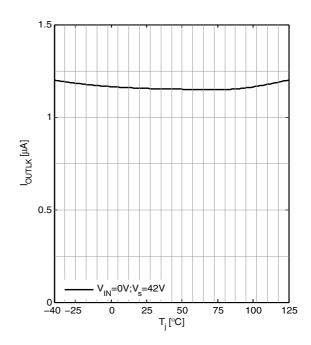


Typical Characterisitics

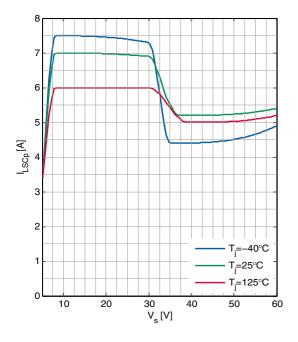
Standby Current $I_{\rm SSTB}$ versus Junction Temperature $T_{\rm i}$



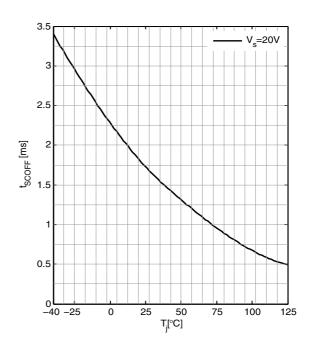
Output Leakage current $I_{\rm OUTLK}$ versus Junction Temperature $T_{\rm i}$



Initial Peak Short Circuit Current Limt $I_{\rm LSCP}$ versus Junction Temperature $T_{\rm i}$



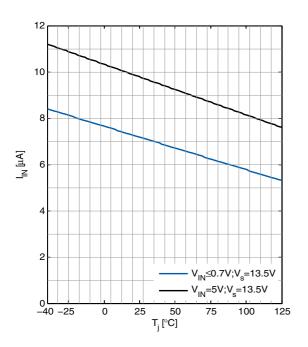
Initial Short Circuit Shutdown time $t_{\rm SCOFF}$ versus Junction Temperature $T_{\rm i}$



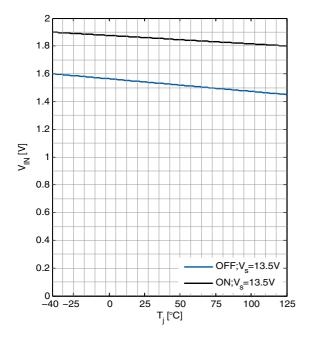


Typical Characterisitics

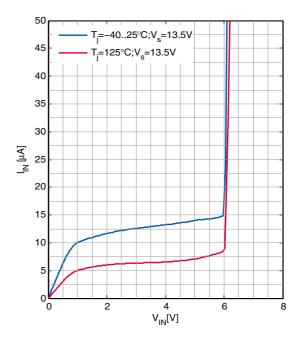
Input Current Consumption $I_{\rm IN}$ versus Junction Temperature $T_{\rm j}$



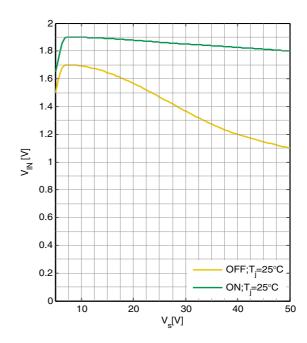
Input Threshold voltage $V_{\mathrm{INH,L}}$ versus Junction Temperature T_{i}



Input Current Consumption I_{IN} versus Input voltage V_{IN}



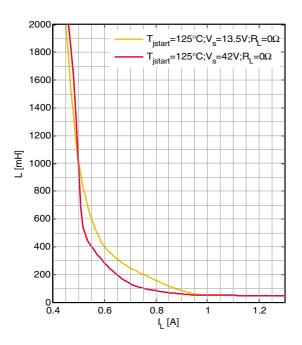
Input Threshold voltage $V_{\rm INH,L}$ versus Supply Voltage $V_{\rm S}$



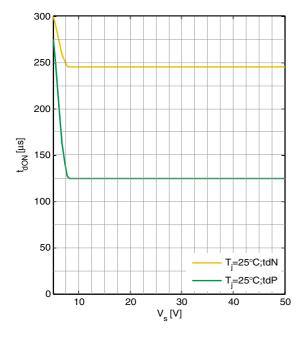


Typical Characterisitics

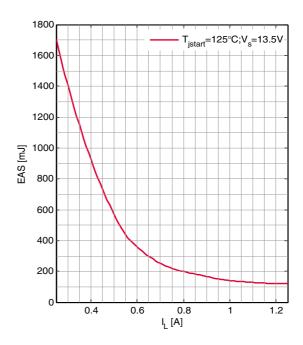
Max. allowable Load Inductance L versus Load current $I_{\rm L}$



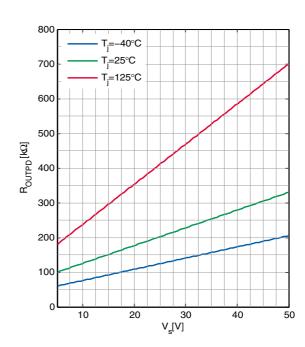
Status Delay Time $t_{\rm N,\,P}$ versus Supply Voltage $V_{\rm S}$



Max. allowable Inductive single pulse Switch-off Energy $E_{\rm AS}$ versus Load current $I_{\rm L}$



Internal Output pull down Resistor R_{OUTOPD} versus Supply Voltage V_{S}





7 Application Information

7.1 Application Diagram

The following information is given as a hint for the implementation of the device only and shall not be regarded as a description or warranty for a certain functionality, condition or quality of the device.

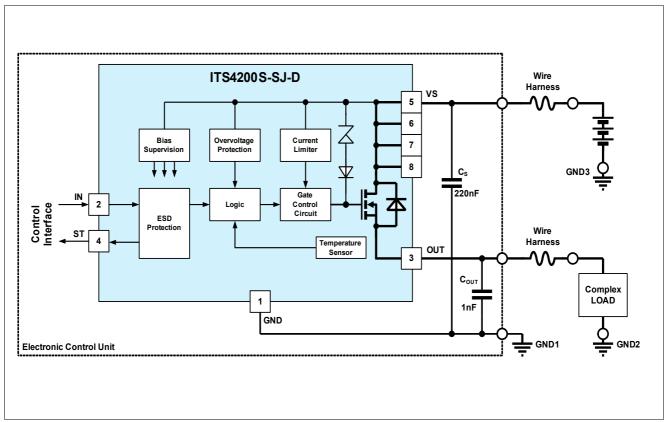


Figure 4 Application Diagram

The ITS4200S-SJ-D can be connected directly to the battery of a supply network. It is recommended to place a ceramic capacitor (e.g. $C_S = 220$ nF) between supply and GND of the ECU to avoid line disturbances. Wire harness inductors/resistors are sketched in the application circuit above.

The complex load (resistive, capacitive or inductive) must be connected to the output pin OUT.

A built-in current limit protects the device against destruction.

The ITS4200S-SJ-D can be switched on and off with standard logic ground related logic signal at pin IN.

In standby mode (IN=L) the ITS4200S-SJ-D is deactivated with very low current consumption.

The output voltage slope is controlled during on and off transistion to minimize emissions. Only a small ceramic capacitor COUT=1nF is recommended to attenuate RF noise.

In the following chapters the main features, some typical waverforms and the protection behaviour of the ITS4200S-SJ-D is shown. For further details please refer to application notes on the Infineon homepage.



7.2 Diagnosis Description

For diagnostic purpose the device provides a digital output pin ST in order to indicate fault conditions.

The status output (ST) of the ITS4200S-SJ-D is a high voltage open drain output.

In "normal" operation mode the NMOS open drain transistor is switched OFF.

The following truth table defines the status output.

Table 5 Truth Table of diagnosis feature

Device Operation	IN	OUT	ST	Comment
Normal Operation	L	L	Н	
Normal Operation	Н	Н	Н	
Short circuit to GND	L	L	Н	
Short circuit to GND	Н	L	L	OUT=L: $V_{\rm OUT}$ < $V_{\rm OUTSC}$; Short circuit detection voltage; typ 2.8V
Short Circuit to V _S (in OFF state	L	Н	L	
Short Circuit to V _S (in OFF state	Н	Н	Н	
Overload	L	L	Н	
Overload	Н	Н	Н	OUT=H: $V_{\rm OUT} > V_{\rm OUTSC}$; Short circuit detection voltage; typ 2.8V
Overtemperature	L	L	Н	
Overtemperature	Н	L	L	
Open Load in OFF state	L	Z	Н	OUT=Z: high impedance; potential depends on external circuit
Open Load in OFF state	L	Н	L	with external resistor between $V_{\rm S}$ and OUT

7.3 Special Feature Description



Supply over voltage:

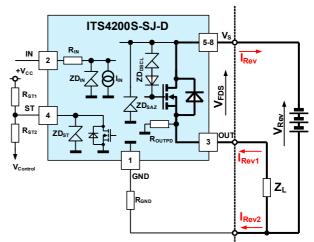
ITS4200S-SJ-D IN 2 ZD_N ZD_{ST} ZD_{ST} R_{OUTPD} 3 OUT R_{GND} R_{GND} ZL R_{OUTPD} ZL

If over-voltage is applied to the V_S -Pin: Voltage is limited to V_{ZDSAZ} ; current can be calculated: $I_{ZDSAZ} = (V_S - V_{ZDSAZ}) / R_{GND}$

A typical value for RGND is 150 $\!\Omega.$

In case of ESD pulse on the input pin there is in both polarities a peak current $I_{INpeak} \sim V_{ESD} / R_{IN}$

Supply reverse voltage:



If reverse voltage is applied to the device:

1.) Current via load resistance RL:

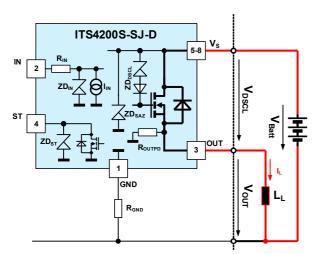
$$I_{Rev1} = (V_{Rev} - V_{FDS}) / R_L$$

2.) Current via Input pin IN and dignostic pin ST:

$$\begin{split} I_{Rev2} &= I_{ST} + I_{IN} \sim (V_{Rev} - V_{CC})/R_{IN} + (V_{Rev} - V_{CC})/R_{ST1,2} \\ \text{Current } I_{ST} \text{ must be limited with the extrernal series} \\ \text{resistor } R_{STS}. \text{ Both currents will sum up to:} \end{split}$$

$$I_{Rev} = I_{Rev1} + I_{Rev2}$$

Drain-Source power stage clamper V_{DSCL}:

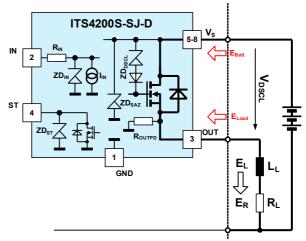


When an inductive load is switched off a current path must be established until the current is sloped down to zero (all energy removed from the inductive load). For that purpose the series combination Z_{DSCL} is connected between Gate and Drain of the power DMOS acting as an active clamp.

When the device is switched off, the voltage at OUT turns negative until V_{DSCI} is reached.

The voltage on the inductive load is the difference between V_{DSCL} and $V_{\text{S}}.$

Energy calculation:



Energy stored in the load inductance is given by : $E_1 = I_1^{2*}L/2$

While demagnetizing the load inductance the energy dissipated by the Power-DMOS is:

$$E_{AS} = E_S + E_L - E_R$$

With an approximate solution for $R_L = 0\Omega$: $E_{AS} = \frac{1}{2} * L * I_L^2 * \{(1 - V_S / (V_S - V_{DSCL}))\}$

Figure 5 Special feature description

7.4 Typical Application Waveforms

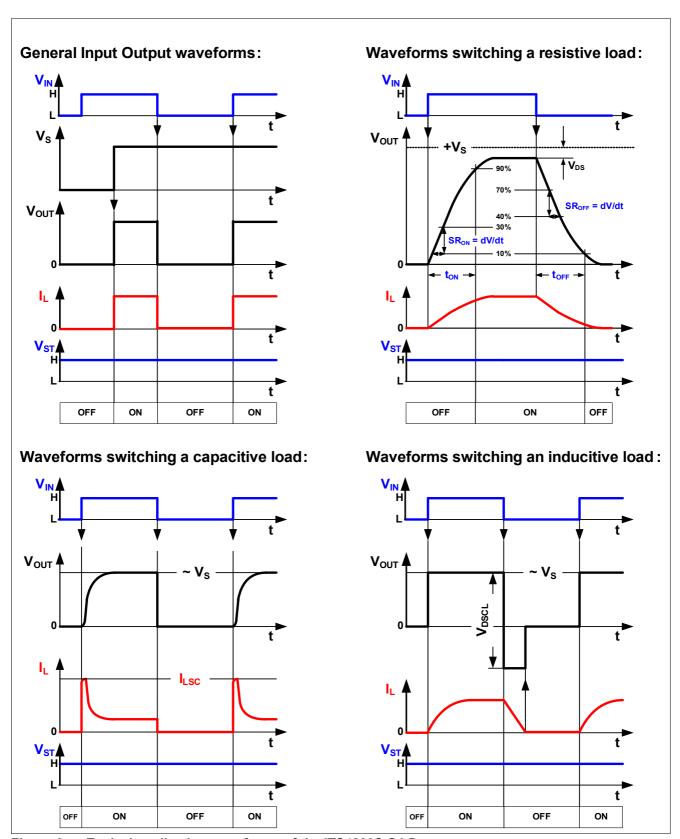


Figure 6 Typical application waveforms of the ITS4200S-SJ-D

7.5 Protection Behavior

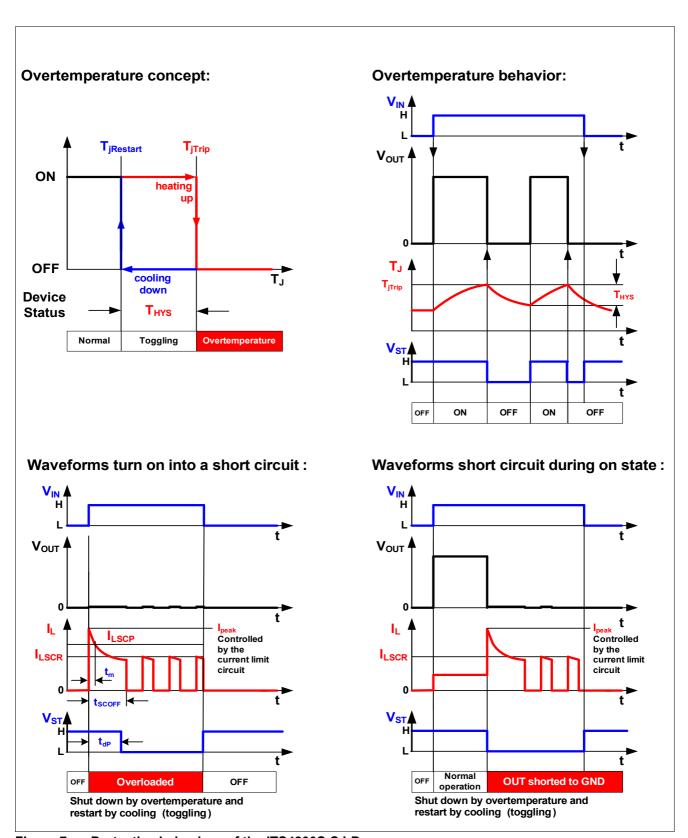


Figure 7 Protective behaviour of the ITS4200S-SJ-D



Package outlines and footprint

8 Package outlines and footprint

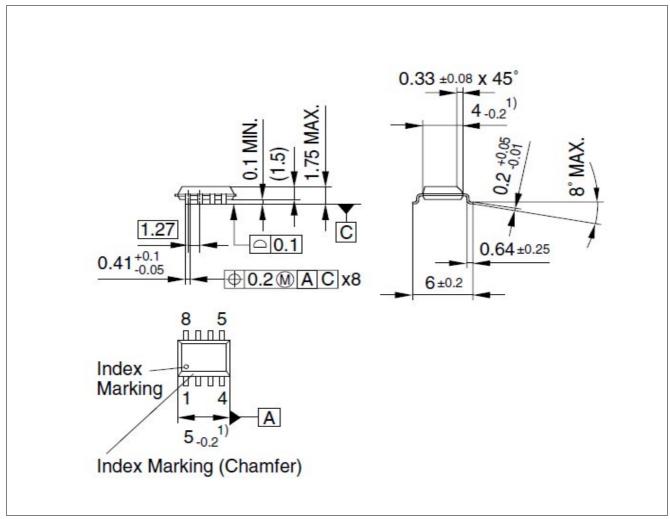


Figure 8 PG-DSO-8 (Plastic Dual Small Outline Package, RoHS-Compliant)

To meet the world-wide customer requirements for environmentally friendly products and to be compliant with government regulations the device is available as a green product. Green products are RoHS-Compliant (i.e Pb-free finish on leads and suitable for Pb-free soldering according to IPC/JEDEC J-STD-020



Revision History

9 Revision History

Revision	Date	Changes
V 1.0	12-09-01	Datasheet release

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